Notice of References Cited Application/Control No. 10/849,050 Examiner Derick G. Jackson Applicant(s)/Patent Under Reexamination KIM ET AL. Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-2004/0120247 A1	06-2004	Lee et al.	369/275.3
*	В	US-2003/0067858	04-2003	Kuroda et al.	369/59.24
*	С	US-6,847,599 B2	01-2005	Hayashi, Tsuneo	369/53.22
*	D	US-7,006,419	02-2006	Yokoi, Kenya	369/59.11
	Ε	US-			
	F	US-			
	G	US-			
	Н	US-			
	1	US-			
	J	US-			
	K	US-			
	L	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	EP 703576 A1	03-1996	European Patent	OZAKI et al.	
	0	EP 997899 A2	05-2000	European Patent	MURAKAMI et al.	
	Р					
	Q	•				
	R					
	S					
	Т					

NON-PATENT DOCUMENTS

	NON-I ATENT DOCUMENTO					
*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)				
	U					
	v					
	w					
	×					

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

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